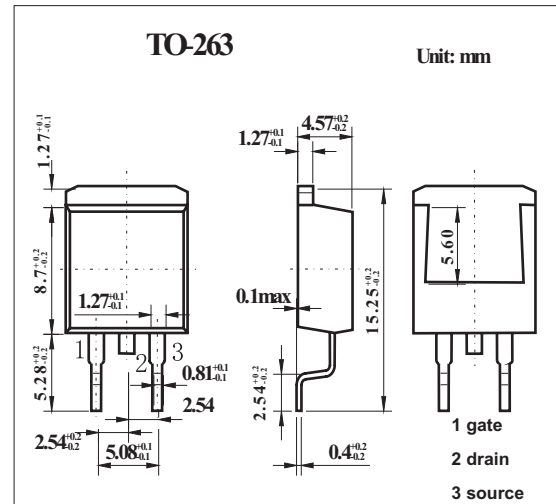
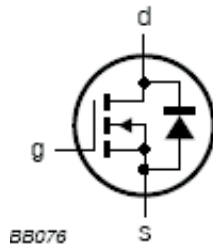


## TrenchMOS™ standard level FET

### KUK7109-75ATE

#### ■ Features

- Integrated temperature sensor
- Electrostatic discharge protection
- Q101 compliant
- Standard level compatible.



#### ■ Absolute Maximum Ratings $T_a = 25^\circ\text{C}$

Parameter	Symbol	Rating	Unit
Drain-source voltage	$V_{DS}$	75	V
Drain-gate voltage $R_{GS} = 20\text{ K}\Omega$	$V_{DGR}$	75	V
Gate-source voltage	$V_{GS}$	$\pm 20$	V
Drain current (DC) $T_{mb} = 25^\circ\text{C}, V_{GS} = 10\text{ V}$	$I_D$	120	A
Drain current (DC) $T_{mb} = 100^\circ\text{C}, V_{GS} = 10\text{ V}$	$I_D$	75	A
Drain current (pulse peak value) *1	$I_{DM}$	480	A
Total power dissipation $T_{mb} = 25^\circ\text{C}$	$P_{tot}$	272	W
gate-source clamping current (continuous)	$I_{GS(CL)}$	10	mA
gate-source clamping current *3		50	mA
FET to temperature sense diode isolation voltage	$V_{isol}(FET-TSD)$	$\pm 100$	V
Storage & operating temperature	$T_{stg}, T_j$	-55 to 175	$^\circ\text{C}$
reverse drain current (DC) $T_{mb} = 25^\circ\text{C}$	$I_{DR}$	120	A
		75	A
pulsed reverse drain current *1	$I_{DRM}$	480	A
non-repetitive avalanche energy *2	$E_{DS(AL)S}$	739	J
Thermal resistance junction to mounting base	$R_{th\ j-mb}$	0.55	K/W
Thermal resistance junction to ambient	$R_{th\ j-a}$	50	K/W

\* 1  $T_{mb} = 25^\circ\text{C}$ ; pulsed;  $t_p \leq 10\ \mu\text{s}$ ;

\* 2 unclamped inductive load;  $I_D = 75\text{ A}; V_{DS} \leq 75\text{ V}; V_{GS} = 10\text{ V}; R_{GS} = 50\Omega$ ; starting  $T_j = 25^\circ\text{C}$

\* 3  $t_p = 5\text{ ms}; \delta = 0.01$

## KUK7109-75ATE

## ■ Electrical Characteristics Ta = 25°C

Parameter	Symbol	Testconditions	Min	Typ	Max	Unit
drain-source breakdown voltage	V <sub>(BR)DSS</sub>	I <sub>D</sub> = 0.25 mA; V <sub>GS</sub> = 0 V; T <sub>J</sub> = 25°C	75			V
		I <sub>D</sub> = 0.25 mA; V <sub>GS</sub> = 0 V; T <sub>J</sub> = -55°C	70			V
gate-source threshold voltage	V <sub>GS(th)</sub>	I <sub>D</sub> = 1 mA; V <sub>DS</sub> = V <sub>GS</sub> ; T <sub>J</sub> = 25°C	2	3	4	V
		I <sub>D</sub> = 1 mA; V <sub>DS</sub> = V <sub>GS</sub> ; T <sub>J</sub> = 175°C	1			V
		I <sub>D</sub> = 1 mA; V <sub>DS</sub> = V <sub>GS</sub> ; T <sub>J</sub> = -55°C			4.4	V
Zero gate voltage drain current	I <sub>DSS</sub>	V <sub>DS</sub> = 75 V; V <sub>GS</sub> = 0 V; T <sub>J</sub> = 25°C		0.1	10	μA
		V <sub>DS</sub> = 75 V; V <sub>GS</sub> = 0 V; T <sub>J</sub> = 175°C			250	μA
gate-source breakdown voltage	V <sub>(BR)GSS</sub>	I <sub>G</sub> = ±1 mA; -55°C < T <sub>J</sub> < 175°C	20	22		
gate-source leakage current	I <sub>GSS</sub>	V <sub>GS</sub> = ±10 V; V <sub>DS</sub> = 0 V; T <sub>J</sub> = 25°C		22	1000	nA
		V <sub>GS</sub> = ±10 V; V <sub>DS</sub> = 0 V; T <sub>J</sub> = 175°C			10	μA
drain-source on-state resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> = 10 V; I <sub>D</sub> = 50 A; T <sub>J</sub> = 25°C	.	8	9	mΩ
		V <sub>GS</sub> = 10 V; I <sub>D</sub> = 50 A; T <sub>J</sub> = 175°C			19	mΩ
forward voltage; temperature sense diode	V <sub>F</sub>	I <sub>F</sub> = 250 mA	648	658	668	mV
temperature coefficient temperature sense diode	S <sub>F</sub>	I <sub>F</sub> = 250 mA; -55°C < T <sub>J</sub> < 175°C	-1.4	-1.54	-1.68	mV/K
temperature sense diode forward voltage hysteresis	V <sub>hys</sub>	125 mA < I <sub>F</sub> < 250 mA	25	32	50	mV
total gate charge	Q <sub>g(tot)</sub>	V <sub>GS</sub> = 10 V; V <sub>DD</sub> = 60 V; I <sub>D</sub> = 25 A		121		nC
gate-to-source charge	Q <sub>gs</sub>		20		nC	
gate-to-drain (Miller) charge	Q <sub>gd</sub>		44		nC	
input capacitance	C <sub>iss</sub>	V <sub>GS</sub> = 0 V; V <sub>DS</sub> = 25 V; f = 1 MHz		4700	3760	pF
output capacitance	C <sub>oss</sub>		800	665	pF	
reverse transfer capacitance	C <sub>rss</sub>		455	274	pF	
turn-on delay time	t <sub>d(on)</sub>	V <sub>DD</sub> = 30 V; R <sub>L</sub> = 1.2Ω; V <sub>GS</sub> = 10 V; R <sub>G</sub> = 10Ω		35		ns
rise time	t <sub>r</sub>		108		ns	
turn-off delay time	t <sub>d(off)</sub>		185		ns	
fall time	t <sub>f</sub>		100		ns	
internal drain inductance	L <sub>d</sub>	measured from upper edge of drain mounting base to center of die		2.5		nH
internal source inductance	L <sub>s</sub>	measured from source lead to source bond pad		7.5		nH
source-drain (diode forward) voltage	V <sub>SD</sub>	I <sub>S</sub> = 25A; V <sub>GS</sub> = 0 V		0.85	1.2	V
reverse recovery time	t <sub>rr</sub>	I <sub>S</sub> = 20 A; -di <sub>F</sub> /dt = -100 A/μs;		75		ns
recovered charge	Q <sub>r</sub>	V <sub>GS</sub> = -10 V; V <sub>DS</sub> = 30 V		270		nC